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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/824,123	04/13/2004	Nianci Han	003330	6448
61285	7590	04/10/2008	P01/ETCH/METAL/MD	
JANAH & ASSOCIATES, P.C. 650 DELANCEY STREET, SUITE 106 SAN FRANCISCO, CA 94107			EXAMINER LAVILLA, MICHAEL E	
			ART UNIT	PAPER NUMBER
			1794	
			MAIL DATE	DELIVERY MODE
			04/10/2008	PAPER

**Please find below and/or attached an Office communication concerning this application or proceeding.**

The time period for reply, if any, is set in the attached communication.

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APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION	ATTORNEY DOCKET NO.
10824123	4/13/04	HAN ET AL.	003330

P01/ETCH/METAL/MD

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**EXAMINER**

Michael La Villa

ART UNIT	PAPER
1794	20080408

DATE MAILED:

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**Commissioner for Patents**

Applicant's IDS, having a mail receipt date of 6 March 2008, has been considered and an Examiner-initialed copy is enclosed. Document KR 10-375080 has not been initialed because no relevance or translation was provided.

With respect to the IDS of 13 April 2000 (20040413), on page 2 thereof, Document US 6,123,791, published on 26 September 2000 to Han et al., is indicated as having been considered by the Examiner. The typographical error of this entry in the originally filed 1449 has been corrected, and Examiner initials have been provided next to the corrected document number.

Michael La Villa  
8 April 2008

/Michael La Villa/  
Primary Examiner, Art Unit 1794